Agilent Technologies to Display Innovations in Design, Test Capabilities at IEEE MTT-S IMS 2009

Agilent Technologies Inc. demonstrated its newest innovations in design and measurement solutions for advanced RF and microwave research, development and manufacturing at the IEEE MTT-S International Microwave Symposium 2009 last week. Connecting experts to experts, the popular MicroApps Theater, sponsored by Agilent, will offer 19 MicroApps sessions. Planned topics include front-to-back MMIC design flow including nonlinear parameter extraction, nonlinear network analysis, wideband signal analysis, and simulation and design of software-defined radios. A full list of papers and an online registration form are available at www.agilent.com/find/IMS2009. Agilent showcased the following products at IEEE MTT-S IMS 2009: Accurate Nonlinear Device Measurements: The Agilent PNA-X Nonlinear Vector Network Analyzer (NVNA), based on the PNA-X, measures nonlinear device characteristics and gives accurate insight into the nonlinear behavior of active devices using Agilent's NVNA application software and new calibration phase references. Comprehensive Active-Device Test: The Agilent PNA-X Series network analyzers can measure an amplifier's gain, gain compression, harmonics, IMD and noise figure with one easy setup and without an external combiner or filters. Scanning Microwave Microscopy (SMM): Agilent's Atomic Force Microscope 5420 AFM in conjunction with Agilent's vector network analyzer can be used for high spatial resolution of electromagnetic materials properties. Integrated ADS with Broad Electromagnetic Analysis: EMPro 2009 is full 3-D electromagnetic (EM) design and simulation software. It contains both finite-element-method and finite-difference-time-domain EM simulation techniques, integrated with Advanced Design System (ADS) to allow design simulation and cross-verification of all types of EM analysis problems. Complete, Front-to-Back Solution for MMIC, RF Module Design: Advanced Design System 2009 Update 1 is the industry's first complete, front-to-back solution for monolithic microwave integrated circuit (MMIC) and RF module design integrates electromagnetic analysis, wireless standards-based design verification libraries, X-parameter simulation and statistical design and yield optimization. Microwave Signal Generator that Breaks the One-Watt Output Power Barrier: The Agilent PSG E8257D option 521 signal generator delivers output power in excess of 1 W over most of its frequency range. With specified output power from +24 to +28 dBm over most of its 20 GHz of frequency range, it eliminates the need for additional hardware such as amplifiers, couplers and detectors in most high-power test environments. Advanced Wideband Vector Signal Analysis and Digital Troubleshooting: Agilent's Infiniium 9000 Series oscilloscopes offer the broad measurement capability with true analog bandwidths up to 4 GHz.

Source URL (retrieved on *11/21/2014 - 8:56pm*):
http://www.wirelessdesignmag.com/news/2009/06/agilent-technologies-display-innovations-design-test-capabilities-ieee-mtt-s-ims-2009?qt-digital_editions=0